30V N-Channel Enhancement-Mode MOSFET 30V N 沟道增强型 MOS 管

V_{DS}= 30V

$$\begin{split} R_{DS(ON)}, \, V_{gs}@10V, \, I_{ds}@12A &= 10.5 m\Omega \\ R_{DS(ON)}, \, V_{gs}@4.5V, \, I_{ds}@12A &= 15 m\Omega \end{split}$$

Features 特性

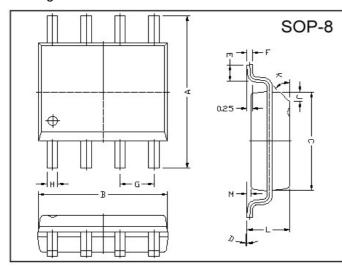
Advanced trench process technology 高级的加工技术

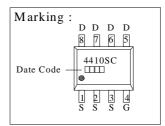
High Density Cell Design For Ultra Low On-Resistance 极低的导通电阻高密度的单元设计

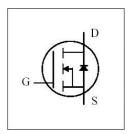
Fully Characterized Avalanche Voltage and Current 完好的雪崩性能

Improved Shoot-Through FOM 改进的成型工艺

Package Dimensions 封装尺寸及外形图







| | Millimeter | | REF. | Millimeter | | |
|------|------------|------|------|------------|------|--|
| REF. | Min. | Max. | KEF. | Min. | Max. | |
| Α | 5.80 | 6.20 | М | 0.10 | 0.25 | |
| В | 4.80 | 5.00 | Н | 0.35 | 0.49 | |
| С | 3.80 | 4.00 | L | 1.35 | 1.75 | |
| D | 0° | 8° | J | 0.375 REF. | | |
| Е | 0.40 | 0.90 | K | 45° | | |
| F | 0.19 | 0.25 | G | 1.27 TYP. | | |

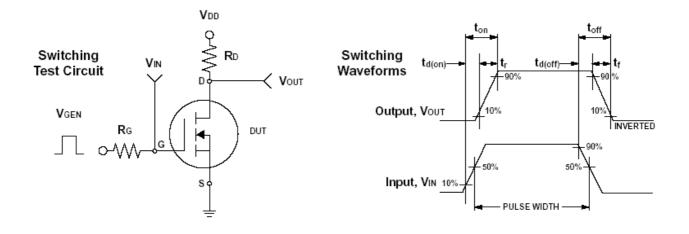
Maximum Ratings and Thermal Characteristics (TA = 25oC unless otherwise noted) 25°C 极限参数和热特性

| Parameter 极限参数 | Symbol 符号 | Limit 范围 | Unit 单位 | | |
|--|-----------------------------------|-----------------|---------|----|----|
| Drain-Source Voltage 漏源电压 | V _{DS} | 30 | V | | |
| Gate-Source Voltage 栅源电压 | V _{GS} | ± 20 | | | |
| Continuous Drain Current 连续漏极电流 | I _D | 12 | А | | |
| Pulsed Drain Current ¹⁾ 脉冲漏极电流 | | I _{DM} | | | 48 |
| Maximum Daylor Dissinction 县土拉坳rh荥 | $TA = 25^{\circ}C$ | P _D | 2.5 | W | |
| Maximum Power Dissipation 最大耗散功率 | TA = 75°C | | 1.2 | ٧٧ | |
| Operating Junction and Storage Temperature Range 使用及储存 | T _J , T _{stg} | -55 to 150 | °C | | |
| Avalanche Energy with Single Pulse 雪崩能量 | EAS | 150 | mJ | | |
| Junction-to-Case Thermal Resistance 结壳热阻 | $R_{	heta JC}$ | 25 | °C/W | | |
| Junction-to-Ambient Thermal Resistance (PCB mounted) 2) 结环 | $R_{	hetaJA}$ | 50 | | | |

| FLECTRICAL CHARACTERISTICS — 船由与结 | FI FCTRICAL |
|-----------------------------------|-------------|
|-----------------------------------|-------------|

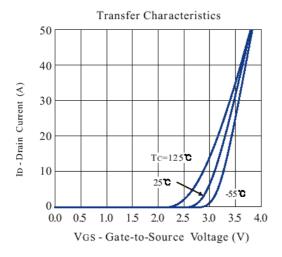
| Parameter 参数 | 符号 | Test Condition 测试条件 | 最小值 | 典型值 | 最大值 | 单位 |
|--|---------------------|--|-----|------|------|-----|
| Static 静态参数 | | | | | | |
| Drain-Source Breakdown Voltage 漏源击穿电压 | BV_{DSS} | $V_{GS} = 0V, I_D = 250uA$ | 30 | | | V |
| Drain-Source On-State Resistance 漏源导通电阻 | R _{DS(on)} | $V_{GS} = 4.5V, I_D = 12A$ | | 11.0 | 15.0 | m() |
| Drain-Source On-State Resistance 漏源导通电阻 | R _{DS(on)} | $V_{S(on)} V_{GS} = 10V, I_D = 12A$ | | 8.5 | 10.5 | mΩ |
| Gate Threshold Voltage 开启电压 | V _{GS(th)} | $V_{DS} = V_{GS}$, $I_D = 250uA$ | 1 | 1.8 | 3 | V |
| Zero Gate Voltage Drain Current 0 栅压漏极电流 | I _{DSS} | $V_{DS} = 24V$, $V_{GS} = 0V$ | | | 1 | uA |
| Gate Body Leakage 漏极短路时截止栅电流 | I _{GSS} | $V_{GS} = \pm 20V, V_{DS} = 0V$ | | | ±100 | nA |
| Forward Transconductance 正向跨导 | g fs | $V_{DS} = 15V, I_D = 12A$ | | 64 | _ | S |
| Dynamic ³⁾ 动态参数 | | | | | | |
| Total Gate Charge 栅极总电荷 | Q_g | $V_{DS} = 15V, I_{D} = 12A$ | | 12 | 45 | nC |
| Gate-Source Charge 栅-源极电荷 | Q_{gs} | $V_{GS} = 13V, I_D = 12A$ $V_{GS} = 5V$ | | 4.5 | | |
| Gate-Drain Charge 栅-漏极电荷 | Q_{gd} | V GS = 3 V | | 3.6 | | |
| Turn-On Delay Time 导通延迟时间 | t _{d(on)} | | | 22 | 35 | |
| Turn-On Rise Time 导通上升时间 | t _r | V_{DD} = 15V, R_G = 6Ω | | 13 | 20 | ns |
| Turn-Off Delay Time 关断延迟时间 | $t_{\text{d(off)}}$ | $I_D = 1A, V_{GS} = 10V$ | | 82 | 125 | 115 |
| Turn-Off Fall Time 关断下降时间 | t _f | | | 30 | 45 | |
| Input Capacitance 输入电容 | C _{iss} | $V_{DS} = 15V, V_{GS} = 0V$ | | 1180 | | pF |
| Output Capacitance 输出电容 | Coss | -v _{DS} = 15v, v _{GS} = 0v -f = 1.0 MHz | | 270 | | |
| Reverse Transfer Capacitance 反向传输电容 | C_{rss} | 7 - 1.0 | | 145 | | |
| Source-Drain Diode 源漏二极管参数 | | | | | | |
| Max. Diode Forward Current 最大正向电流 | Is | | | | 2.0 | А |
| Diode Forward Voltage 正向电压 | V_{SD} | $I_S = 2A$, $V_{GS} = 0V$ | | | 1.5 | V |

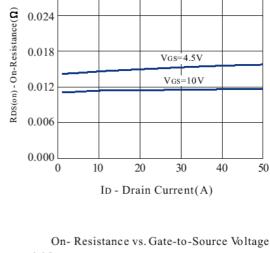
Note: Pulse test: pulse width <= 300us, duty cycle<= 2% 注意: 脉冲测试: 脉冲宽度<= 300us 死区<= 2%



N-Channel 30-V (D-S) MOSFET

Typical Characteristics (T_J =25℃ Noted)





0.030

On-Resistance vs. Drain Current

